

41
Docket No. 215686US99CIP

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Fred RICHARD, et al.

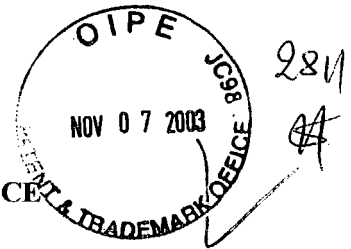
SERIAL NO: 09/985,757

GAU: 2811

FILED: November 6, 2001

EXAMINER: HU, S.

FOR: MICROCAVITY SEMICONDUCTOR LASER COUPLED TO A WAVEGUIDE



INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- ☒ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

Richard L. Treanor

Registration No. 36,379

RECEIVED
NOV 21 2003
TECHNOLOGY CENTER 2801

11/10/2003 SHINASS1 00000024 09985757

01 FC:1806

180.00 OP

Customer Number

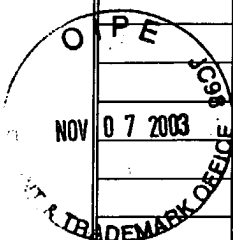
22850

Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 05/03)

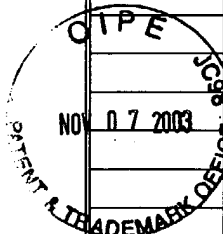
Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	3,802,967	04/09/74	Ladany et al.			
	AB	4,174,422	11/13/79	Matthews et al.			
	AC	4,404,265	09/13/83	Manasevit			
	AD	4,482,906	11/13/84	Hovel et al.			
	AE	4,523,211	06/11/85	Morimoto et al.			
	AF	4,661,176	04/28/87	Manasevit			
	AG	4,793,872	12/27/88	Meunier et al.			
	AH	4,846,926	07/11/89	Kay et al.			
	AJ	4,855,249	08/08/89	Akasaki et al.			
	AI	4,891,091	01/02/90	Shastry			
	AK	4,912,087	03/27/90	Aslam et al.			
	AL	4,928,154	05/22/90	Umeno et al.			
	AM	4,963,949	10/16/90	Wanlass et al.			
	AN	5,141,894	08/25/92	Bisaro et al.			
	AO	5,159,413	10/27/92	Calviello et al.			
	AP	5,173,474	12/22/92	Connell et al.			
	AQ	5,221,367	06/22/93	Chisholm et al.			
	AR	5,225,031	07/06/93	McKee et al.			
	AS	5,358,925	10/25/94	Neville Connell et al.			
	AT	5,393,352	02/28/95	Summerfelt			
	AU	5,418,216	05/23/95	Fork			
	AV	5,450,812	09/19/95	McKee et al.			
	AW	5,478,653	12/26/95	Guenzer			
	AX	5,482,003	01/09/96	McKee et al.			
	AY	5,514,484	05/07/96	Nashimoto			
	AZ	5,556,463	09/17/96	Guenzer			
	BA	5,588,995	12/31/96	Sheldon			
	BB	5,670,798	09/23/97	Schetzina			
	BC	5,733,641	03/31/98	Fork et al.			
	BD	5,735,949	04/07/98	Mantl et al.			
	BE	5,741,724	04/21/98	Ramdani et al.			
	BF	5,810,923	09/22/98	Yano et al.			
	BG	5,830,270	11/03/98	McKee et al.			
	BH	5,912,068	06/15/99	Jia			
	BI	6,020,222	02/01/00	Wollesen			
	BJ	6,045,626	04/04/00	Yano et al.			
	BK	6,064,078	05/16/00	Northrup et al.			
	BL	6,064,092	05/16/00	Park			
	BM	6,096,584	08/01/00	Ellis-Monaghan et al.			
	BN	6,103,008	08/15/00	McKee et al.			
	BO	6,136,666	10/24/00	So			
	BP	6,174,755	01/16/01	Manning			



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	CA	3,766,370	10/16/73	Walther			
	CB	4,006,989	02/08/77	Andringa			
	CC	4,284,329	08/18/81	Smith et al.			
	CD	4,777,613	10/11/98	Shahan et al.			
	CE	4,802,182	01/31/89	Thornton et al.			
	CF	4,882,300	11/21/89	Inoue et al.			
	CG	4,896,194	01/23/90	Suzuki			
	CH	4,999,842	03/12/91	Huang et al.			
	CI	5,081,062	01/14/92	Vasudev et al.			
	CJ	5,155,658	10/13/92	Inam et al.			
	CK	5,248,564	09/28/93	Ramesh			
	CL	5,260,394	11/09/93	Tazaki et al.			
	CM	5,270,298	12/14/93	Ramesh			
	CN	5,286,985	02/15/94	Taddiken			
	CO	5,310,707	05/10/94	Oishi et al.			
	CP	5,326,721	07/05/94	Summerfelt			
	CQ	5,404,581	04/04/95	Honjo			
	CR	5,418,389	05/23/95	Watanabe			
	CS	5,436,759	07/25/95	Dijai et al.			
	CT	5,576,879	11/19/96	Nashimoto			
	CU	5,606,184	02/25/97	Abrokwhah, et al.			
	CV	5,640,267	06/17/97	May et al.			
	CW	5,674,366	10/07/97	Hayashi et al.			
	CX	5,729,641	03/17/98	Chandonnet et al.			
	CY	5,790,583	08/04/98	Ho			
	CZ	5,825,799	10/20/98	Ho et al.			
	DA	5,857,049	01/05/99	Beranek et al.			
	DB	5,874,860	02/23/99	Brunel et al.			
	DC	5,926,496	07/20/99	Ho et al.			
	DD	5,937,285	08/10/99	Abrokwhah, et al.			
	DE	5,981,400	11/09/99	Lo			
	DF	5,990,495	11/23/99	Ohba			
	DG	6,002,375	12/14/99	Corman et al.			
	DH	6,008,762	12/28/99	Nghiem			
	DI	6,055,179	04/25/00	Koganei et al.			
	DJ	6,107,653	08/22/00	Fitzgerald			
	DK	6,113,690	09/05/00	Yu et al.			
	DL	6,114,996	09/05/00	Nghiem			
	DM	6,121,642	09/19/00	Newns			
	DN	6,128,178	10/03/00	Newns			
	DO	6,143,072	11/07/00	McKee et al.			



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	EA	4,484,332	11/20/84	Hawrylo			
	EB	4,815,084	03/21/89	Scifres et al.			
	EC	4,876,219	10/24/89	Eshita et al.			
	ED	4,963,508	10/16/90	Umeno et al.			
	EE	5,060,031	10/22/91	Abrokwhah, et al.			
	EF	5,063,166	11/05/91	Mooney et al.			
	EG	5,116,461	05/26/92	Lebby et al.			
	EH	5,127,067	06/30/92	Delcoco et al.			
	EI	5,144,409	09/01/92	Ma			
	EJ	5,293,050	03/08/94	Chapple-Sokol et al			
	EK	5,356,831	10/18/94	Calviello et al.			
	EL	5,391,515	02/21/95	Kao et al.			
	EM	5,442,191	08/15/95	Ma			
	EN	5,444,016	08/22/95	Abrokwhah, et al.			
	EO	5,480,829	01/02/96	Abrokwhah, et al.			
	EP	5,528,414	06/18/96	Oakley			
	EQ	5,614,739	03/25/97	Abrokwhah et al.			
	ER	5,729,394	03/17/98	Sevier et al.			
	ES	5,731,220	03/24/98	Tsu et al.			
	ET	5,764,676	06/09/98	Paoli et al.			
	EU	5,777,762	07/07/98	Yamamoto			
	EV	5,778,018	07/07/98	Yoshikawa et al.			
	EW	5,778,116	07/07/98	Tomich			
	EX	5,801,105	09/01/98	Yano et al.			
	EY	5,828,080	10/27/98	Yano et al.			
	EZ	5,858,814	01/12/99	Goossen et al.			
	FA	5,861,966	01/19/99	Ortel			
	FB	5,883,996	03/16/99	Knapp et al.			
	FC	5,995,359	11/30/99	Klee et al.			
	FD	6,058,131	05/02/00	Pan			
	FE	6,137,603	10/24/00	Henmi			
	FF	6,146,906	11/14/00	Inoue et al.			
	FG	6,173,474	01/16/01	Conrad			
	FH	6,180,252	01/30/01	Farrell et al.			
	FI	4,242,595	12/30/0	Lehovec			
	FJ	4,398,342	08/16/83	Pitt et al.			
	FK	4,424,589	01/03/84	Thomas et al.			
	FL	4,876,208	10/24/89	Gustafson et al.			
	FM	4,482,422	11/84	McGinn et al.			
	FN	4,667,088	05/19/87	Kramer			
	FO	4,772,929	09/20/88	Manchester et al.			
	FP	4,841,775	06/27/89	Ikeda et al.			



Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

November 6, 2001

GROUP

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	GA	4,868,376	09/19/89	Lessin et al.			
	GB	4,885,376	12/05/89	Verkade			
	GC	4,888,202	12/89	Murakami et al.			
	GD	4,891,091	12/90	Wanlass et al.			
	GE	5,051,790	09/24/91	Hammer			
	GF	5,055,445	10/08/91	Belt et al.			
	GG	5,081,519	11/14/92	Nishimura et al.			
	GH	5,143,854	09/01/92	Pirrung et al.			
	GI	5,185,589	02/09/93	Krishnaswamy et al.			
	GJ	5,191,625	03/02/93	Gustavsson			
	GK	5,194,397	03/16/93	Cook et al.			
	GL	5,208,182	05/04/93	Narayan et al.			
	GM	5,216,729	06/01/93	Berger et al.			
	GN	5,314,547	05/24/94	Heremans et al.			
	GO	5,352,926	10/04/94	Andrews			
	GP	5,356,509	10/18/94	Terranova et al.			
	GQ	5,371,734	12/06/94	Fischer			
	GR	5,372,992	12/94	Itozaki et al.			
	GS	5,405,802	04/11/95	Yamagata et al.			
	GT	5,442,561	08/15/95	Yoshizawa et al.			
	GU	5,453,727	09/26/95	Shibasaki et al.			
	GV	5,466,631	11/14/95	Ichikawa et al.			
	GW	5,473,047	12/05/95	Shi			
	GX	5,473,171	12/95	Summerfelt			
	GY	5,479,033	12/26/95	Baca et al.			
	GZ	5,486,406	01/23/96	Shi			
	HA	5,491,461	02/13/96	Partin et al.			
	HB	5,492,859	02/20/96	Sakaguchi et al.			
	HC	5,494,711	02/27/96	Takeda et al.			
	HD	5,504,035	04/02/96	Rostoker et al.			
	HE	5,504,183	04/02/96	Shi			
	HF	5,511,238	04/23/96	Bayraktaroglu			
	HG	5,512,773	04/96	Wolf et al.			
	HH	5,515,047	05/07/96	Yamakido et al.			
	HI	5,515,810	05/14/96	Yamashita et al.			
	HJ	5,519,235	05/96	Ramesh			
	HK	5,549,977	08/96	Jin et al.			
	HL	5,551,238	09/03/96	Prueitt			
	HM	5,552,547	09/03/96	Shi			
	HN	5,589,284	12/31/96	Summerfelt et al.			
	HO	5,602,418	02/11/97	Imai et al.			
	HP	5,633,724	05/27/97	King et al.			

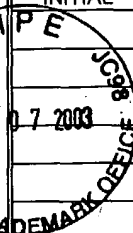
O I P E

NOV 07 2003

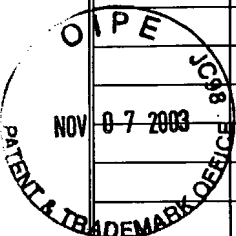
PCT & TRADEMARK OFFICE

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	IA	5,650,646	07/22/97	Summerfelt			
	IB	5,656,382	08/12/97	Nashimoto			
	IC	5,659,180	08/19/97	Shen et al.			
	ID	5,661,112	08/26/97	Hatta et al.			
	IE	5,679,965	11/95	Schetzina			
	IF	5,725,641	03/10/98	MacLeod			
	IG	5,745,631	04/28/98	Reinker			
	IH	5,776,621	07/07/98	Nashimoto			
	II	5,777,350	07/07/98	Nakamura et al.			
	IJ	5,789,845	08/04/98	Wadaka et al.			
	IK	5,792,569	08/11/98	Sun et al.			
	IL	5,792,679	08/11/98	Nakato			
	IM	5,796,648	08/18/98	Kawakubo et al.			
	IN	5,801,072	09/01/98	Barber			
	IO	5,812,272	09/22/98	King et al.			
	IP	5,814,583	09/98	Itozaki et al.			
	IQ	5,825,055	10/20/98	Summerfelt			
	IR	5,827,755	10/27/98	Yonchara et al.			
	IS	5,833,603	11/10/98	Kovacs et al.			
	IT	5,838,035	11/17/98	Ramesh			
	IU	5,844,260	12/01/98	Ohori			
	IV	5,846,846	12/08/98	Suh et al.			
	IW	5,863,326	01/26/99	Nause et al.			
	IX	5,872,493	02/16/99	Ella			
	IY	5,879,956	03/99	Seon et al.			
	IZ	5,880,452	03/09/99	Plesko			
	JA	5,883,564	03/16/99	Partin			
	JB	5,907,792	05/25/99	Droopad et al.			
	JC	5,937,274	08/10/99	Kondow et al.			
	JD	5,948,161	09/07/99	Kizuki			
	JE	5,959,879	09/28/99	Koo			
	JF	5,966,323	10/99	Chen et al.			
	JG	5,987,011	11/16/99	Toh			
	JH	6,022,140	02/08/00	Fraden et al.			
	JI	6,022,410	02/08/00	Yu et al.			
	JJ	6,023,082	02/08/00	McKee et al.			
	JK	6,028,853	02/22/00	Haartsen			
	JL	6,049,702	04/11/00	Tham et al.			
	JM	6,078,717	06/20/00	Nashimoto et al			
	JN	6,088,216	07/00	Laibowitz et al.			
	JO	6,090,659	07/00	Laibowitz et al.			
	JP	6,107,721	08/22/00	Lakin			

NOV 07 2003
PTO
TRADEMARK OFFICE

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	KA	6,153,454	11/28/00	Krivokapic			
	KB	6,191,011	02/01	Gilboa et al.			
	KC	6,204,737	03/20/01	Ella			
	KD	6,224,669	05/01/01	Yi et al.			
	KE	6,225,051	05/01/01	Sugiyama et al.			
	KF	6,241,821	06/05/01	Yu et al.			
	KG	6,265,749	07/24/01	Gardner et al.			
	KH	6,313,486	11/01	Kencke et al.			
	KI	6,316,832	11/13/01	Tsuzuki et al.			
	KJ	2002/0008234	01/02	Emrick			
	KK	3,670,213	06/13/72	Nakawaga et al.			
	KL	4,756,007	07/05/88	Qureshi et al.			
	KM	4,773,063	09/20/88	Hunsperger et al.			
	KN	5,394,489	02/28/95	Koch			
	KO	5,406,202	04/11/95	Mehrgardt et al.			
	KP	5,528,067	06/18/96	Farb et al.			
	KQ	5,572,052	11/05/96	Kashihara et al.			
	KR	5,767,543	06/16/98	Ooms et al.			
	KS	6,175,497	01/16/01	Tseng et al.			
	KT	6,197,503	03/06/01	Vo-Dinh et al.			
	KU	6,248,459	06/19/01	Wang et al.			
	KV	6,252,261	06/26/01	Usui et al.			
	KW	6,255,198	07/03/01	Linthicum et al.			
	KX	6,268,269	07/31/01	Lee et al.			
	KY	6,291,319	09/18/01	Yu et al.			
	KZ	6,316,785	11/13/01	Nunoue et al.			
	LA	6,343,171	01/29/02	Yoshimura et al.			
	LB	4,965,649	10/23/90	Zanio et al.			
	LC	6,253,649	05/01	Kawahara et al.			
	LD	6,211,096	04/01	Allman et al.			
LE	6,239,449	05/29/01	Fafard et al.				
LF	2001/0013313	08/16/01	Droopad et al.				
LG	6,184,044	02/06/01	Sone et al.				
LH	6,011,646	01/04/00	Mirkarimi et al.				
LI	5,227,196	07/13/93	Itoh				
LJ	6,150,239	11/21/00	Goesele et al.				
LK	5,441,577	08/15/95	Sasaki et al.				
LL	4,459,325	07/10/84	Nozawa et al.				
LM	4,392,297	07/12/83	Little				
LN	4,289,920	09/15/81	Hovel				
LO	5,281,834	01/25/94	Cambou et al.				

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	MA	5,553,089	09/03/96	Seki et al.			
	MB	5,528,057	06/18/96	Yanagase et al.			
	MC	6,229,159	05/08/01	Suzuki			
	MD	4,748,485	05/31/88	Vasudev			
	ME	4,984,043	01/08/91	Vinal			
	MF	5,754,319	05/19/98	Van De Voorde et al.			
	MG	6,108,125	08/22/00	Yano			
	MH	5,073,981	12/17/91	Giles et al.			
	MI	5,140,651	08/18/92	Soref et al.			
	MJ	5,610,744	03/11/97	Ho et al.			
	MK	6,362,017	03/26/02	Manabe et al.			
	ML	6,242,686	06/05/01	Kishimoto et al.			
	MM	5,689,123	11/18/97	Major et al.			
	MN	5,670,800	09/23/97	Nakao et al.			
	MO	5,067,809	11/26/91	Tsubota			
	MP	5,596,205	01/21/97	Reedy et al.			
	MQ	6,175,555	01/16/01	Hoole			
	MR	5,357,122	10/18/94	Okubora et al.			
	MS	4,084,130	04/11/78	Holton			
	MT	6,093,302	07/25/00	Montgomery			
	MU	6,372,813	04/16/02	Johnson et al.			
	MV	5,608,046	03/04/97	Cook et al.			
	MW	5,955,591	09/21/99	Imbach et al.			
	MX	6,022,963	02/08/00	McGall et al.			
	MY	6,083,697	07/04/00	Beecher et al.			
	MZ	5,063,081	11/05/91	Cozzette et al.			
	NA	5,479,317	12/26/95	Ramesh			
	NB	5,306,649	04/26/94	Hebert			
	NC	5,962,069	10/05/99	Schindler et al.			
	ND	5,541,422	07/30/96	Wolf et al.			
	NE	5,873,977	02/23/99	Desu et al.			
	NF	5,538,941	07/23/96	Findikoglu et al.			
	NG	6,046,464	04/04/00	Schetzina			
	NH	6,235,145	05/22/01	Li et al.			
	NI	5,610,744	03/11/97	Ho et al.			
	NJ	5,280,013	01/18/94	Newman et al.			
	NK	6,348,373 B1	02/19/02	Ma et al.			
	NL	6,339,664 B1	01/15/02	Farjady et al.			
	NM	4,439,014	03/27/84	Stacy et al.			
	NN	4,889,402	12/26/89	Reinhart			
	NO	5,963,291	10/05/99	Wu et al.			
	NP	6,011,641	01/04/00	Shin et al.			
	NQ	6,340,788 B1	01/22/02	King et al.			



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
FILING DATE November 6, 2001				GROUP 2811			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	OA	5,807,440	09/15/98	Kubota et al.			
	OB	4,681,982	07/21/87	Yoshida			
	OC	4,629,821	12/16/86	Bronstein-Bonte et al.			
	OD	4,452,720	06/05/84	Harada et al.			
	OE	3,935,031	01/27/76	Adler			
	OF	5,760,426	06/02/98	Marx et al.			
	OG	5,053,835	10/01/91	Horikawa et al.			
	OH	6,326,645 B1	12/04/01	Kadota			
	OI	5,770,887	06/23/98	Tadatomoto et al.			
	OJ	6,372,356 B1	04/16/02	Thornton et al.			
	OK	4,774,205	09/27/88	Choi et al.			
	OL	6,359,330 B1	03/19/02	Goudard			
	OM	5,312,765	05/17/94	Kanber			
	ON	5,734,672	03/31/98	McMinn et al.			
	OO	6,367,699 B2	04/09/02	Ackley			
	OP	5,530,235	06/25/96	Stefik et al.			
	OQ	5,623,552	04/22/97	Lane			
	OR	5,481,102	01/02/96	Hazelrigg, Jr.			
	OS	6,134,114	10/17/00	Ungermann et al.			
	OT	5,984,190	11/16/99	Nevill			
	OU	5,789,733	08/04/98	Jachimowicz et al.			
	OV	5,753,300	05/19/98	Wessels et al.			
	OW	6,208,453	03/27/01	Wessels et al.			
	OX	5,886,867	03/23/99	Chivukula et al.			
	OY	5,028,976	07/02/91	Ozaki et al.			
	OZ	5,869,845	02/09/99	Vander Wagt et al.			
	PA	5,596,214	01/21/97	Endo			
	PB	6,391,674 B2	05/21/02	Ziegler			
	PC	6,275,122 B1	08/14/01	Speidell et al.			
	PD	6,238,946 B1	05/29/01	Ziegler			
	PE	6,210,988 B1	04/03/01	Howe et al.			
	PF	6,392,257	05/21/02	Ramdani et al.			
	PG	4,442,590	04/17/84	Stockton et al.			
	PH	5,603,764	02/18/97	Matsuda et al.			
	PI	6,087,681	06/11/00	Shakuda			
	PJ	5,132,648	07/21/92	Trinh et al.			
	PK	6,427,066	07/30/02	Grube			
	PL	2002/0072245	06/13/02	Ooms et al.			
	PM	6,278,138 B1	08/21/01	Suzuki			
	PN	5,888,296	03/30/99	Ooms et al.			
	PO	5,198,269	03/30/93	Swartz et al.			
	PP	6,000,000,000	03/14/02	Fischer et al.			

NOV 07 2003
 PTO
 PATENT & TRADEMARK OFFICE

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	QA	5,776,359	07/07/98	Schultz et al.			
	QB	5,569,953	10/29/96	Kikkawa et al.			
	QC	5,834,362	11/10/98	Miyagaki et al.			
	QD	6,248,621 B1	06/19/01	Wilk et al.			
	QE	5,266,355	11/30/93	Wernberg et al.			
	QF	6,277,436 B1	08/21/01	Stauf et al.			
	QG	6,039,803	03/21/00	Fitzgerald et al.			
	QH	5,619,051	04/08/97	Endo			
	QI	5,420,102	05/30/95	Harshavardhan et al.			
	QJ	5,210,763	05/11/93	Lewis et al.			
	QK	5,103,494	04/07/92	Mozer			
	QL	4,594,000	06/10/86	Falk et al.			
	QM	4,297,656	10/27/81	Pan			
	QN	5,244,818	09/14/93	Jokers et al.			
	QO	6,048,751	04/11/00	D'Asaro et al.			
	QP	5,484,664	01/16/96	Kitahara et al.			
	QQ	5,780,311	07/14/98	Beasom et al.			
	QR	6,438,281 B1	08/20/02	Tsukamoto et al.			
	QS	5,399,898	03/21/95	Rostoker			
	QT	6,271,619	08/07/01	Yamada et al.			
	QU	5,334,556	08/02/94	Guldi			
	QV	4,910,164	03/20/90	Shichijo			
	QW	4,952,420	08/28/90	Walters			
	QX	6,121,647	09/19/00	Yano et al.			
	QY	6,306,668 B1	10/23/01	McKee et al.			
	QZ	6,143,366	11/07/00	Lu			
	RA	6,410,941	06/25/02	Taylor et al.			
	RB	5,397,428	03/14/95	Stoner et al.			
	RC	6,432,546 B1	08/13/02	Ramesh et al.			
	RD	6,345,424	02/12/02	Hasegawa et al.			
	RE	6,338,756 B2	01/15/02	Dietze			
	RF	5,516,725	05/14/96	Chang et al.			
	RG	4,667,212	05/19/87	Nakamura			
	RH	5,629,534	05/13/97	Inuzuka et al.			
	RI	3,914,137	10/21/75	Huffman et al.			
	RJ	5,753,928	05/19/98	Krause			
	RK	5,977,567	11/02/99	Verdiell			
	RL	5,130,762	07/14/92	Kulick			
	RM	5,621,227	04/15/97	Joshi			
	RN	6,389,209 B1	05/14/02	Suhir			
	RO	5,163,118	11/10/92	Lorenzo et al.			
	RP	5,926,493	07/20/99	O'Brien et al.			

NOV 7 2003
U.S. PATENT & TRADEMARK OFFICE

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	SA	6,156,581	12/05/00	Vaudo et al.			
	SB	5,395,663	03/07/95	Tabata et al.			
	SC	4,146,297	03/27/79	Alferness et al.			
	SD	5,452,118	09/19/95	Maruska			
	SE	5,889,296	03/30/99	Imamura et al.			
	SF	6,300,615 B1	10/09/01	Shinohara et al.			
	SG	6,232,910 B1	05/15/01	Bell et al.			
	SH	5,686,741	11/11/97	Ogori et al.			
	SI	4,959,702	09/25/90	Moyer et al.			
	SJ	6,100,578	08/08/00	Suzuki			
	SK	6,410,947 B1	06/25/02	Wada			
	SL	6,417,059 B2	07/09/02	Huang			
	SM	6,461,927 B1	10/08/02	Mochizuki et al.			
	SN	6,462,360 B1	10/08/02	Higgins, Jr. et al.			
	SO	5,981,976	11/09/99	Murasato			
	SP	5,981,980	11/09/99	Miyajima et al.			
	SQ	2002/0006245 A1	01/17/02	Kubota et al.			
	SR	2002/0131675 A1	09/19/02	Litvin			
	SS	6,256,426 B1	07/03/01	Duchet			
	ST	6,278,523 B1	08/21/01	Gorecki			
	SU	6,319,730 B1	11/20/01	Ramdani et al.			
	SV	6,404,027	06/11/02	Hong et al.			
	SW	6,312,819 B1	11/06/01	Jia et al.			
	SX	5,119,448	06/02/92	Schaefer et al.			
	SY	4,120,588	10/17/78	Chaum			
	SZ	5,194,917	03/16/93	Regener			
	TA	5,018,816	05/28/91	Murray et al.			
	TB	5,953,468	09/14/99	Finnila et al.			
	TC	5,561,305	10/01/96	Smith			
	TD	5,896,476	04/20/99	Wisseman et al.			
	TE	4,934,777	06/19/90	Jou et al.			
	TF	6,320,238 B1	11/20/01	Kizilyalli et al.			
	TG	6,393,167 B1	05/21/02	Davis et al.			
	TH	5,760,427	06/02/98	Onda			
	TI	6,411,756 B2	06/25/02	Sadot et al.			
	TJ	5,668,048	09/16/97	Kondo et al.			
	TK	5,852,687	12/22/98	Wickham			
	TL	5,122,852	06/16/92	Chan et al.			
	TM	5,173,835	12/22/92	Cornett et al.			
	TN	5,055,835	10/08/91	Sutton			
	TO	6,139,483	10/31/00	Seabaugh et al.			
	TP	5,283,462	02/01/94	Stengel			
	TQ	6,402,402	08/15/00	Grigorian et al.			

NOV 07 2003
U.S. PATENT & TRADEMARK OFFICE

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

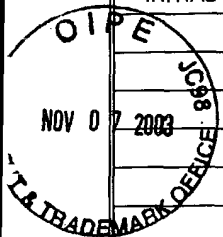
November 6, 2001

GROUP

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	UA	5,635,433	06/03/97	Sengupta			
	UB	5,427,988	06/27/95	Sengupta et al.			
	UC	6,297,842 B1	10/02/01	Koizumi et al.			
	UD	5,682,046	10/28/97	Takahashi et al.			
	UE	5,181,085	01/19/93	Moon et al.			
	UF	6,051,858	04/18/00	Uchida et al.			
	UG	6,013,553	01/11/00	Wallace et al.			
	UH	4,872,046	10/03/89	Morkoc et al.			
	UI	2002/0047123 A1	04/25/02	Ramdani et al.			
	UJ	5,995,528	11/30/99	Fukunaga et al.			
	UK	5,075,743	12/24/91	Behfar-Rad			
	UL	5,438,584	08/01/95	Paoli et al.			
	UM	4,503,540	03/05/85	Nakashima et al.			
	UN	5,373,166	12/13/94	Buchan et al.			
	UO	6,278,137 B1	08/21/01	Shimoyama et al.			
	UP	5,623,439	04/22/97	Gotoh et al.			
	UQ	4,981,714	01/01/91	Ohno et al.			
	UR	6,194,753 B1	02/27/01	Seon et al.			
	US	6,326,637 B1	12/04/01	Parkin et al.			
	UT						
	UU						
	UV						
	UW						
	UX						
	UY						
	UZ						
	VA						
	VB						
	VC						
	VD						
	VE						
	VF						
	VG						
	VH						
	VI						
	VJ						
	VK						
	VL						
	VM						
	VN						
	VO						
	VP						



Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

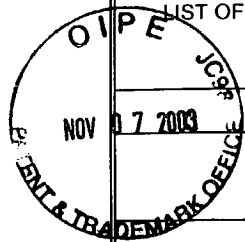
November 6, 2001

GROUP

2811

U.S. PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AAA	0 250 171	12/23/87	EP	X	
	AAB	0 342 937	11/23/89	EP	X	
	AAC	0 455 526	06/11/91	EP	X	
	AAD	0 602 568	06/22/94	EP	X	
	AAE	0 607 435	07/27/94	EP	X	
	AAF	1 001 468	05/17/00	EP	X	
	AAG	0 514 018	11/19/92	EP	X	
	AAH	0 999 600	05/10/00	EP	X	
	AAI	1 319 311	06/04/70	Great Britain	X	
	AAJ	5-291299	11/05/93	Japan w/English Abstract	X	
	AAK	11-238683	08/31/99	Japan	X	
	AAL	11-260835	09/24/99	Japan w/English Abstract	X	
	AAM	HEI 2-391	01/05/90	Japan w/English Abstract	X	
	AAN	5-48072	02/26/93	Japan w/English Abstract	X	
	AAO	52-88354	07/23/77	Japan w/English Abstract	X	
	AAP	54-134554	10/19/79	Japan w/English Abstract	X	
	AAQ	55-87424	07/02/80	Japan w/English Abstract	X	
	AAR	61-108187	05/26/86	Japan w/English Abstract	X	
	AAS	6-232126	08/19/94	Japan	X	
	AAT	6-291299	10/18/94	Japan w/English Abstract	X	
	AAU	63-34994	02/15/88	Japan w/English Abstract	X	
	AAV	63-131104	06/03/88	Japan w/English Abstract	X	
	AAW	63-198365	08/17/88	Japan w/English Abstract	X	
	AAX	10-321943	12/04/98	Japan	X	
	AAY	6-334168	12/02/94	Japan	X	
	AAZ	WO 99/63580	12/09/99	WIPO	X	
	ABA	WO 99/14804	03/25/99	WIPO	X	
	ABB	WO 97/45827	12/04/97	WIPO		
	ABC	WO 99/19546	04/22/99	WIPO		
	ABD	WO 00/33363	06/08/00	WIPO		
	ABE	WO 00/48239	08/17/00	WIPO		
	ABF	WO 99/14797	03/25/99	WIPO		
	ABG	GB 2 335 792	09/29/99	Great Britain		
	ABH	1 109 212	06/20/01	Europe		
	ABI	DE 197 12 496	10/30/97	Germany		X
	ABJ	60-212018	10/24/85	Japan w/English Abstract		
	ABK	60-210018	10/22/85	Japan w/English Abstract		
	ABL	WO 92/10875	06/25/92	WIPO		
	ABM	0 682 266	11/15/95	Europe		
	ABN	3-41783	02/91	Japan (English Abstract only)		
	ABO	0 581 239	02/02/94	Europe		
	ABP	0812494	01/16/96	Japan		



Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

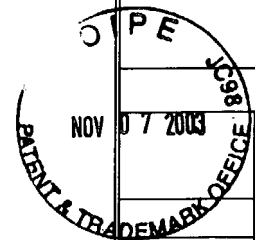
November 6, 2001

GROUP

2811

U.S. PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	BAA	1 043 426	10/11/00	Europe		
	BAB	2000-068466	03/00	Japan (Abstract)		
	BAC	64-50575	02/27/89	Japan		
	BAD	WO 98/05807	01/12/98	WIPO		
	BAE	WO 94/03908	02/17/94	WIPO		
	BAF	WO 01/33585	05/10/01	WIPO		
	BAG	1-102435	04/20/89	Japan w/English Abstract		
	BAH	52-135684	11/12/77	Japan (English Abstract)		
	BAI	02051220	02/21/90	Japan (English Abstract)		
	BAJ	11135614	05/21/99	Japan (w/English Abstract)		
	BAK	64-52329	02/28/89	Japan (w/English Abstract)		
	BAL	10-256154	09/25/98	Japan (w/English Abstract)		
	BAM	DE 196 07 107	08/28/97	Germany		xx
	BAN	10-303396	11/13/98	Japan (w/English Abstract)		
	BAO	58-213412	12/12/83	Japan w/English Abstract		
	BAP	0 964 259	12/15/99	Europe		
	BAQ	0 875 922	11/04/98	Europe		
	BAR	61-63015	04/01/86	Japan w/English Abstract		
	BAS	11340542	12/10/99	Japan (English Abstract)		
	BAT	WO 01/37330	05/25/01	WIPO		
	BAU	0 331 467	09/06/89	Europe		
	BAV	WO 00/16378	03/23/00	WIPO		
	BAW	0 926 739	06/30/99	Europe		
	BAX	0 964 453	12/15/99	Europe		
	BAY	5-152529	06/18/93	Japan w/English Abstract		
	BAZ	9-67193	03/11/97	Japan w/English Abstract		
	BBA	9-82913	03/28/97	Japan w/English Abstract		
	BBB	0 309 270	03/29/89	Europe		
	BBC	EP 0 957 522	11/17/99	Europe		
	BBD	EP 0 810 666	12/03/97	Europe		
	BBE	1-179411	07/17/89	Japan w/English Abstract		
	BBF	DE 100 17 137	10/26/00	GERMANY		
	BBG	WO 02 01648	01/03/02	WIPO		
	BBH	WO 02/33385 A2	04/25/02	WIPO		
	BBI	WO 01/59814 A2	08/16/01	WIPO		
	BBJ	WO 02/09160 A2	01/31/02	WIPO		
	BBK	WO 00/06812	02/10/00	WIPO		
	BBL	0 483 993	05/06/92	Europe		
	BBM	0 538 611	04/28/93	Europe		
	BBN	WO 01/59820 A1	08/16/01	WIPO		
	BBO	05150143	06/18/93	Japan (English Abstract only)		
	BBP	2 779 843	12/17/99	France		xx



Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

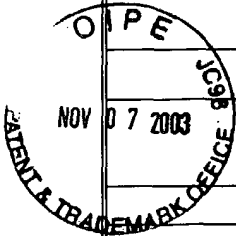
November 6, 2001

GROUP

2811

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
				YES	NO
CAA	52-89070	07/26/77	Japan	xx	
CAB	EP 1 069 606	01/17/01	Europe		
CAC	WO 02/03113	01/10/02	WIPO		
CAD	WO 02/03467	01/10/02	WIPO		
CAE	0 630 057	12/21/94	EUROPE		
CAF	61-36981	02/21/86	Japan w/English Abstract		
CAG	WO 93/07647	04/15/93	WIPO		
CAH	2002-9366	01/11/02	Japan w/English Abstract		
CAI	EP 0 881 669	12/02/98	Europe		
CAJ	WO 02/03480	01/10/02	WIPO		
CAK	WO 02/50879	06/27/02	WIPO		
CAL	EP 0 777 379	06/04/97	Europe		
CAM	WO 01/04943 A1	01/18/01	WIPO		XX
CAN	WO 02/47127 A2	06/13/02	WIPO		
CAO	JP 58-075868	05/07/83	Japan w/English Abstract		
CAP	EP 0 993 027	04/12/00	Europe		
CAQ	EP 0 711 853	05/15/96	Europe		
CAR	WO 98/20606	05/14/98	WIPO		
CAS	EP 1 043 765	10/11/00	Europe		
CAT	0 300 499	01/25/89	Europe		
CAU	EP 1 085 319	03/21/01	Europe		
CAV	WO 01/16395	03/08/01	WIPO		
CAW	2000-351692	12/19/00	Japan w/English Abstract		
CAX	03-188619	08/16/91	Japan (English Abstract only)		
CAY	63-289812	11/28/88	Japan (English Abstract only)		
CAZ	EP 0 884 767	12/16/98	Europe		
CBA	06-069490	03/11/94	Japan (English Abstract only)		
CBB	WO 01/59821 A1	08/16/01	WIPO		
CBC					
CBD					
CBE					
CBF					
CBG					
CBH					
CBI					
CBJ					
CBK					
CBL					
CBM					
CBN					
CBO					
CBP					



Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 215686US99CIP	SERIAL NO. 09/985,757
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Fred RICHARD, et al.	
FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
CCAA	Nakagawara et al., "Effects of Buffer Layers in Epitaxial Growth of SrTiO ₃ Thin Film on Si(100), <i>J. Appl. Phys.</i> , 78 (12), December 15, 1995, pp. 7226-7230.		
CCAB	Suzuki et al., "A Proposal of Epitaxial Oxide Thin Film Structures For Future Oxide Electronics," <i>Materials Science and Engineering B41</i> , (1996), pp. 166-173.		
CCAC	W. F. Egelhoff et al., "Optimizing GMR Spin Valves: The Outlook for Improved Properties", <i>1998 Int'l Non Volatile Memory Technology Conference</i> , pp. 34-37.		
CCAD	Wang et al., "Processing and Performance of Piezoelectric Films", Univ. Of MD, Wilcoxon Research Col, and Motorola Labs, May 11, 2000.		
CCAE	M. Rotter et al., "Nonlinear Acoustoelectric Interactions in GaAs/LiNbO ₃ Structures", <i>Applied Physics Letters</i> , Vol. 75(7), August 16, 1999, pp. 965-967.		
CCAF	K. Sreenivas et al., "Surface Acoustic Wave Propagation on Lead Zirconate Titanate Thin Films," <i>Appl. Phys. Lett.</i> 52 (9), Feb. 29, 1998, pp. 709-711.		
CCAG	M. Rotter et al., "Single Chip Fused Hybrids for Acousto-Electric and Acousto-Optic Applications," <i>1997 Applied Physics Letters</i> , Vol. 70(16), April 21, 1997, pp. 2097-2099.		
CCAH	A. Mansingh et al., "Surface Acoustic Wave Propagation in PZT/YBCO/SrTiO ₃ and PbTiO ₃ /YBCO/SrTiO ₃ Epitaxial Heterostructures," <i>Ferroelectric</i> , Vol. 224, pages 275-282, 1999.		
CCAI	S. Mathews et al., "Ferroelectric Field Effect Transistor Based on Epitaxial Perovskite Heterostructures", <i>Science</i> , Vol. 276, April 11, 1997, pp. 238-240.		
CCAJ	R. Houdre et al., "Properties of GaAs on Si Grown by Molecular Beam Epitaxy," <i>Solid State and Materials Sciences</i> , Vol. 16, Issue 2, 1990, pp. 91-114.		
CCAK	S. F. Fang et al., "Gallium Arsenide and Other Compound Semiconductors on Silicon," <i>J. Appl. Phys.</i> , 68(7), October 1, 1990, pp. R31-R58.		
CCAL	Carlin et al., "Impact of GaAs Buffer Thickness on Electronic Quality of GaAs Grown on Graded Ge/GeSi/Si Substrates," <i>Appl. Phys. Letter</i> , Vol. 76, No. 14, April 2000, pp. 1884-1886.		
CCAM	Ringel et al., "Epitaxial Integration of III-V Materials and Devices with Si Using Graded GeSi Buffers," <i>27th International Symposium on Compound Semiconductors</i> , Oct. 2000.		
CCAN	Zogg et al., "Progress in Compound-Semiconductor-on-Silicon-Heteroepitaxy with Fluoride Buffer Layers," <i>J. Electrochem Soc.</i> , Vol. 136, No. 3, March 1998, pp. 775-779.		
CCAO	Xiong et al., "Oxide Defined GaAs Vertical-Cavity Surface-Emitting Lasers on Si Substrates," <i>IEEE Photonics Technology Letters</i> , Vol. 12, No. 2, Feb. 2000, pp. 110-112.		
CCAP	Clem et al., "Investigation of PZT/LSCO//Pt//Aerogel Thin Film Composites for Uncooled Pyroelectric IR Detectors," <i>Mat. Res. Soc. Symp. Proc.</i> , Vol. 541, pp. 661-666, 1999.		
CCAQ	Gunapala et al., "Bound-To-Quasi-Bound Quantum-Well Infrared Photodetectors," <i>NASA Tech Brief</i> , Vol. 22, No. 9, September 1998.		
Examiner		Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

NOV 07 2003
 PATENT & TRADEMARK OFFICE

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

November 6, 2001

GROUP

2811

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

- DDAA Abhay M. Joshi et al., "Monolithic InGaAs-on-silicon Wave Infrared Detector Arrays," *Intn. Society for Optical Engineering*, Vol. 2999, pp. 211-224.
- DDAB Bruley et al., "Nanostructure and Chemistry of a (100)MgO/(100) GaAs Interface," *Appl. Phys Lett*, 65(5), Aug. 1994, pp. 564-566.
- DDAC Fork et al., "Epitaxial MgO On Si(001) for Y-Ba-Cu-O Thin Film Growth by Pulsed Laser Deposition," *Appl. Phys Lett.*, 58(20), May 20, 1991, pp. 2294-2296.
- DDAD Himpfel et al., "Dialectrics on Semiconductors," *Materials Science and Engineering*, B1(1988), pp. 9-13.
- DDAE Li et al., "Epitaxial $\text{La}_{0.67}\text{Sr}_{0.33}\text{MnO}_3$ Magnetic Tunnel Junctions," *J. Appl. Phys.* 81(8), Apr. 15, 1997, pp. 5509-5511.
- DDAF O'Donnell et al., "Colossal Magnetoresistance Magnetic Tunnel Junctions Grown by Molecular-Beam Epitaxy," *Appl. Physics Letters*, Vol. 76, No. 14, April 3, 2000, pp. 1914-1916.
- DDAG Mikami et al., "Formation of Si Epi/MgO-Al₂O₃Epi./SiO₂/Si and Its Epitaxial Film Quality," *Fundamental Research Laboratories and Microelectronics Laboratories*, pp. 31-34, 1983.
- DDAH T. Asano et al., "An Epitaxial Si/Insulator/Si Structure Prepared by Vacuum Deposition of CaF₂ and Silicon," *Thin Solid Films*, Vol. 93 (1982), pp. 143-150.
- DDAI T. Chikyow et al., "Reaction and Regrowth Control of CeO₂ on Si(111) Surface for the Silicon-On-Insulator Structure," *Appl. Phys. Lett.*, Vol. 65, No. 8, 22 August 1994, pp. 1030-1032.
- DDAJ J.F. Kang, et al., "Epitaxial Growth of CeO₂(100) Films on Si(100) Substrates by Dual Ion Beams Reactive Sputtering," *Solid State Communications*, Vol. 108, No. 4, pp. 225-227, 1998.
- DDAK R.A. Morgan et al., "Vertical-Cavity Surface-Emitting Lasers Come of Age," *SPIE*, Vol. 2683, pp. 18-29.
- DDAL "Technical Analysis of Qualcomm QCP-800 Portable Cellular Phone (Transmitter Circuitry)," *Talus Corporation, Qualcomm QCP-800 Technical Analysis Report*, December 10, 1996, pp. 5-8.
- DDAM Jo-Ey WONG, et al.; "AN ELECTROSTATICALLY-ACTUATED MEMS SWITCH FOR POWER APPLICATIONS"; *IEEE*, 2000; pp. 633-638
- DDAN T. MIZUNO, et al.; "Electron and Hole Mobility Enhancement in Strained-Si MOSFET's on SiGe-on-Insulator Substrates Fabricated by SIMOX Technology"; *IEEE ELECTRON DEVICE LETTERS*, VOL. 21. NO. 5, MAY 2000; pp. 230-232
- DDAO F.M. BUFFER, et al.; "Strain-dependence of electron transport in bulk Si and deep-submicron MOSFET's" *Computaturl Electronics*, 2000, Book of Abstracts, IWCE Glasgow 2000, 7th Int'l Workshop on, 2000; pp. 64-65
- DDAP S.S. LU, et al.; "Piezoelectric field effect transistor (PEFET) using In_{0.2}Ga_{0.8}As/Al_{0.35}Ga_{0.65}As/In_{0.2}Ga_{0.8}As/GaAs Strained layer structure on (111)B GaAs substrate"; *ELECTRONICS LETTERS*, 12th Ma 1994, Vol. 30, No. 10; pp. 823-825
- DDAQ Kihong KIM, et al." On-Chip Wireless Interconnection with Integrated Antennas"; 2000 *IEEE*; pp. 20.2.1-20.3.4

Examiner

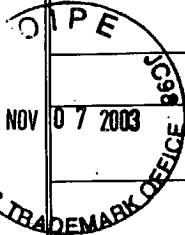
Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

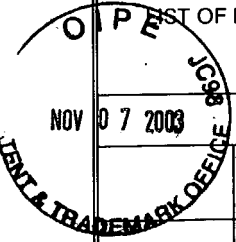
Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
EEAA	G. PASSIOPOULOS, et al.; "V-BAND SINGLE CHIP, DIRECT CARRIER BPSK MODULATION TRANSMITTER WITH INTEGRATED PATCH ANTENNA"; 1998 IEEE MTT-S DIGEST; pp. 305-308						
EEAB	Mau-Chung Frank CHANG, et al.; "RF/Wireless Interconnect for Inter- and Intra-Chip Communications"; Proceedings of the IEEE, Vol. 89, No. 4, April 2001; pp. 456-466						
EEAC	The Electronics Industry Report; Prismark; 2001; pp. 111-120						
EEAD	J.K. ABROKWAH, et al.; "A Manufacturable Complementary GaAs Process"; GaAs IC Symposium, IEEE, 1993; pp. 127-130						
EEAE	H. Nagata, "A Preliminary Consideration of the Growth Behaviour of CeO ₂ , SrTiO ₃ and SrVO ₃ Films on Si Substrate," <i>Thin Solid Films</i> , 224, 1993, pp. 1-3.						
EEAF	Nagata et al., "Heteroepitaxial Growth of CeO ₂ (001) Films on Si(001) Substrates by Pulsed Laser Deposition in Ultrahigh Vacuum," <i>Jpn. Jour. Appl. Phys.</i> , Vol. 30, No. 6B, June 1991, pp. L1136-L1138.						
EEAG	Kado et al., "Heteroepitaxial Growth of SrO Films on Si Substrates," <i>J. Appl. Phys.</i> , 61(6), March 15, 1987, pp. 2398-2400.						
EEAH	H. Ishiwara et al., "Epitaxial Growth of Perovskite Type Oxide Films on Substrates"; <i>Materials Research Symposium Proceedings</i> , Vol. 220, pp. 595-600, April 29 - May 3, 1991.						
EEAI	J.K. Abrokwhah, et al.; "A Manufacturable High-Speed Low-Power Complementary GaAs Process"; Extended Abstracts of the 1994 International Conference on Solid State Devices and Materials, Yokohama, 1994, pp.592-594						
EEAJ	C.J. Palmstrom et al.; "Stable and Epitaxial Contacts to III-V Compound Semiconductors"; <i>Contacts to Semiconductors Fundamentals and Technology</i> ; Noyles Publications, 1993; pp.67-150						
EEAK	Jayshri SABARINATHAT, et al.; "Submicron three-dimensional infrared GaAs/Al _x O _y -based photonic crystal using single-step epitaxial growth"; <i>APPLIED PHYSICS LETTERS</i> , VOLUME 78, NUMBER 20, 14 MAY 2001; pp.3024-3026						
EEAL	Philip BALL; "The Next Generation of Optical Fibers"; <i>Technology Review</i> , May 2001; pp.55-61						
EEAM	John D. JOANNOPOULOS, et al.; "Molding the Flow of Light"; <i>Photonic Crystals</i> ; Princeton University Press, 1995						
EEAN	Thomas F. KRAUSS, et al.; "Photonic crystals in the optical regime - past, present and future"; <i>Progress in Quantum Electronics</i> 23 (1999) 51-96						
EEAO	G. H. JIN, et al.; "PLZT Film Waveguide Mach-Zehnder Electrooptic Modulator"; <i>Journal of Lightwave Technology</i> , Vol. 18, No. 6, June 2000; pp.807-812						
EEAP	D.E. ASPNES, et al.; "Steps on (001) silicon surfaces"; <i>J. Vac. Sci. Technol. B</i> , Vol. 5, No. 4, Jul/Aug 1987; pp. 939-944						
EEAQ	D.M. NEWNS, et al.; "Mott transition field effect transistor"; <i>APPLIED PHYSICS LETTERS</i> , VOLUME 73, NUMBER 6, 10 AUGUST 1998; pp.780-782						
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
FFAA		Lucent Technologies, Inc. "Arrayed Waveguide Grating Multiplexer/Demultiplexer"; January 2000; 4 pages					
FFAB		Hisashi SHICHIJO, et al.; "Co-Integration of GaAs MESFET and Si CMOS Circuits"; IEEE ELECTRON DEVICE LETTERS, VOL. 9, NO. 9, SEPTEMBER 1988; pp.444-446					
FFAC		H. SHICHIJO, et al.; "GaAs MESFET and Si CMOS Cointegration and Circuit Techniques"; 1988 IEEE; GaAs IC Symposium - 239-242					
FFAD		H. SHICHIJO, et al.; "Monolithic Process for Co-Integration of GaAs and Silicon Circuits"; 1988 IEEE; pp.778-781					
FFAE		Z.H. ZHU, et al. "Growth of InGaAs multi-quantum wells at 1.3 m wavelength on GaAs compliant substrates"; APPLIED PHYSICS LETTERS, VOLUME 72, NUMBER 20, 18 MAY 1998; pp.2598-2600					
FFAF		Kurt EISENBEISER, et al.; "Metamorphic InAlAs/InGaAs Enhancement Mode HEMT's on GaAs Substrates"; IEEE ELECTRON DEVICE LETTERS, VOL. 20, NO. 10, OCTOBER 1999; pp.507-509					
FFAG		Tomonori NAGASHIMA, et al.; "Three-Terminal Tandem Solar Cells With a Back-Contact Type Bottom Cell" Higashifuji Technical Center, Toyota Motor Corporation; 4 pages					
FFAH		James SCHELLENBERG, et al.; "Low-Loss, Planar Monolithic Baluns for K/Ka-Band Applications"; 1999 IEEE MTT-S Digest; pp.1733-1736					
FFAI		Arnold Leitner et al; "Pulsed Laser Deposition of Superconducting Strontium Titanate Thin-Films"; ; Session K11-Thin Films and Borocarbides; Mixed Session, Wednesday Afternoon; March 19 1997; Room 1202 B, Conv. Center (Abstract)					
FFAJ		R.D. VISPUTE; "High quality optoelectronic grade epitaxial AlN films on -Al ₂ O ₃ , Si and 6H-SiC by pulsed laser deposition"; Thin Solid Films 299 (1997), pp.94-103					
FFAK		T. Warren WEEKS, et al.; "GaN thin films deposited via organometallic vapor phase epitaxy on (6H)-SiC(0001) using high-temperature monocrystalline AlN buffer layers" 320 Applied Physics Letters, Vol. 67, No. 3, 17 July 1995, ppl401-403					
FFAL		Z. YU, et al.; "Epitaxial oxide thin films on Si(001)*"; J. Vac. Sci. Technol. B. Vol. 18, No. 4, Jul/Aug 2000; pp.2139-2145					
FFAM		Gentex Corporate Website; "Photoelectric Smoke Detectors - How They Work; 2001					
FFAN		Jeffrey B. Casady, et al.; "A Hybrid 6H-SiC Temperature Sensor Operational from 25 C to 500 C"; IEEE TRANSACTIONS ON COMPONENTS, PACKAGING, AND MANUFACTURING TECHNOLOGY - PART A, VOL. 19, NO. 3, SEPTEMBER 1996; pp. 416-422					
FFAO		Ronald W. WAYNANT, et al.; "OPTOELECTRONIC INTEGRATED CIRCUITS"; ELECTRO-OPTICS HANDBOOK, McGraw-Hill, Inc., 1994; Chapter Twenty Seven					
FFAP		Antonio MECOZZI, et al.; "The Roles of Semiconductor Optical Amplifiers in Optical Networks"; Optics & Photonics News; March 2001; pp. 37-42					
FFAQ		D.A. FRANCIS, et al.; "A single-chip linear optical amplifier"; OFC, 2001; March 17-22, 2001					
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



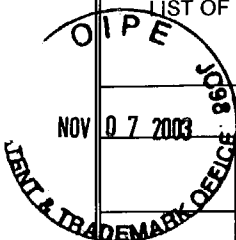
Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 215686US99CIP	SERIAL NO. 09/985,757
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Fred RICHARD, et al.	
		FILING DATE November 6, 2001	GROUP 2811
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
GGAA	G. Vogg et al.; "Epitaxial alloy films of zintl-phase $\text{Ca}(\text{Si}_{1-x}\text{Ge}_x)_2$ "; Journal of Crystal Growth 223 (2001); pp. 573-576		
GGAB	Peter S. GUILFOYLE, et al.; "Optoelectronic Architecture for High-Speed Switching and Processing Applications"; 1998 The Photonics Design and Applications Handbook; pp. H-399-H-406		
GGAC	Gerald B. STRINGFELLOW; "Organometallic Vapor-Phase Epitaxy: Theory and Practice"; Departments of Materials Science and Engineering and Electrical Engineering, University of Utah; Academic Press, 1989		
GGAD	M.A. HERMAN, et al.; "Molecular Beam Epitaxy Fundamentals and Current Status"; Springer-Verlag Berlin Heidelberg, 1989, 1996		
GGAE	"Integration of GaAs on Si Using a Spinel Buffer Layer", IBM Technical Bulletin, Vol. 30, No. 6, Nov. 1987, p. 365.		
GGAF	"GaInAs Superconducting FET," IBM Technical Bulletin, Vol. 36, No. 8, Aug. 1993, p. 655-656.		
GGAG	"Epitaxial 3d Structure Using Mixed Spinel," IBM Technical Bulletin, Vol. 30, No. 3, Aug. 1987, p. 1271.		
GGAH	Moon et al., "Roles of Buffer Layers in Epitaxial Growth of SrTiO_3 Films on Silicon Substrates," <i>Japan J of Appl. Phys.</i> , Vol. 33, March 1994, pp. 1472-1477.		
GGAJ	Yodo et al., GaAs Heteroepitaxial Growth on Si Substrates with Thin Si Interlayers <i>in situ</i> Annealed at High Temperatures," <i>8257b Journal of Vacuum Science & Technology</i> , 1995 May/June, Vol. 13, No. 3, pp. 1000-1005.		
GGAJ	Cuomo et al., "Substrate Effect on the Superconductivity of $\text{YBa}_2\text{Cu}_3\text{O}_7$ Thin Films," AIP Conference 1988, pp. 141-148.		
GGAK	McKee et al., "Crystalline Oxides on Silicon: The First Five Monolayers," <i>Physical Review Letters</i> , Vol. 81, No. 14, Oct. 1998, pp. 3014-3017.		
GGAL	McKee et al., "Molecular Beam Epitaxy Growth of Epitaxial Barium Silicide, Barium Oxide, and Barium Titanate on Silicon," <i>1991 American Institute of Physics</i> , pp. 782-784, August 13, 1991.		
GGAM	Tambo et al., Molecular Beam Epitaxy Growth of SrTiO_3 Films on $\text{Si}(100)\text{-}2\times 1$ with SrO Buffer Layer," <i>Jpn. J. Appl. Phys.</i> , Vol. 37, 1998, pp. 4454-4459.		
GGAN	McKee et al., "The MBE Growth and Optical Quality of BaTiO_3 and SrTiO_3 Thin Films on MgO ," <i>Mat. Res. Soc. Symp. Proc.</i> , Vol. 341, April 1994, pp. 309-314.		
GGAO	McKee et al., " BaSi_2 and Thin Film Alkaline Earth Silicides on Silicon," <i>Appl. Phys. Lett.</i> , 63 (20), Nov. 1993, pp. 2818-2820.		
GGAP	McKee et al., "Surface Structures and the Orthorhombic Transformation of Thin Film BaSi_2 on Silicon," <i>Mat. Res. Soc. Symp. Proc.</i> , Vol. 221, pp. 131-136,		
GGAQ	Brian A. FLOYD, et al.; "The projected Power Consumption of a Wireless Clock Distribution System and Comparison to Conventional Distribution Systems"; IEEE, 1999; pp. IITC99-249-IITC99-250		
Examiner		Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			



Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 215686US99CIP	SERIAL NO. 09/985,757
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Fred RICHARD, et al.	
		FILING DATE November 6, 2001	GROUP 2811
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
HHAA	Mori et al., "Epitaxial Growth of SrTiO ₃ Films on Si(100) Substrates Using a Focused Electron Beam Evaporation Method," <i>Jpn. J. of Apl. Phys.</i> , Vol. 30, No. 8A, Aug. 1991, pp. L1415-L1417.		
HHAB	Moon et al., "Growth of Crystalline SrTiO ₃ Films on Si Substrates Using Thin Fluoride Buffer Layers and Their Electrical Properties," <i>Jpn. J. of Appl. Phys.</i> , Vol. 33, (1994), pp. 5911-5916.		
HHAC	Farrow et al., "Heteroepitaxy of Dissimilar Materials," <i>Mat. Res. Soc. Symposium Proceedings</i> , Vol. 221, pp. 29-34, April 29 - May 2, 1991.		
HHAD	Ishiwara et al., "Heteroepitaxy on Silicon: Fundamentals, Structure, and Devices," <i>Mat. Res. Soc.</i> , Symposium Proceedings, Vol. 116, pp. 369-374, April 5-8, 1988.		
HHA E	Douglas B. Chrisey, et al; Pulsed Laser Deposition of Thin Films; pp. 273-285		
HHA F	B.A. Block, et al; "Photoluminescence properties of Er ³⁺ -doped BaTiO ₃ thin films"; <i>Appl. Phys. Lett.</i> 65 (1), 4 July 1994, pp. 25-27		
HHA G	Kevin J. Chen et al; "A Novel Ultrafast Functional Device: Resonant Tunneling High Electron Mobility Transistor"; <i>Electron Devices Meeting</i> 1996; IEEE Hong Kong; June 29, 1996; pp. 60-63, XP010210167		
HHA H	Wenhua Zhu et al.; "Molecular Beam Epitaxy of GaAs on Si-on-Insulator"; <i>320 Applied Physics Letters</i> 59(1991) 8 July No. 2; pp. 210-212		
HHA I	Umesh K. Mishra et al; "Oxide Based Compound Semiconductor Electronics"; <i>Electron Devices Meeting</i> ; 1997; Technical Digest, International; Washington, D.C.; 7-10 December 1997; pp. 545-548		
HHA J	J.M. Daughton et al.; "Applications of Spin Dependent Transport Materials"; <i>J. Phys. D. Appl. Phys.</i> 32(1999) R169-R177		
HHA K	Wei Zhang et al.; "Stress Effect and Enhanced Magnetoresistance in La _{0.67} Ca _{0.33} MnO _{3-δ} Films"; <i>Physical Review, B. Condensed Matter</i> ; American Institute of Physics; Vol. 58, No. 21, Part 1; December 1, 1998; pp. 14143-14146		
HHA L	Q.-Y. Tong et al.; "IOS-a new type of materials combination for system-on-a chip preparation"; <i>1999 IEEE International SOI Conference</i> , Oct. 1999; pp.104-105		
HHA M	T. Kannianen et al.; "Growth of Dielectric 1hfo2/Ta2O5 Thin Film Nanolaminate Capacitors By Atomic Layer Epitaxy"; <i>Electrochemical Society Proceedings</i> , U.S. Electrochemical Society; Pennington, N.J.; August 31, 1997; pp. 36-46		
HHA N	Myung Bok Lee; "Heteroepitaxial Growth of BaTiO ₃ Films on Si by Pulsed Laser Deposition"; <i>Applied Physics Letters</i> ; March 13, 1995; pp. 1331-1333		
HHA O	Myung Bok Lee; "Formation and Characterization of Eptiaxial TiO ₂ and BaTiO ₃ /TiO ₂ Films on Si Substrate"; <i>Japan Journal Applied Physics Letters</i> ; Vol. 34; 1995; pp. 808-811		
HHA P	Gilbert Lecarpentier et al.; "High Accuracy Machine Automated Assembly for Opto Electronics"; <i>2000 Electronic Components and Technology Conference</i> ; pp. 1-4		
HHA Q	R. Ramesh; "Ferroelectric La-Sr-Co-O/Pb-Zr-Ti-O/La-Sr-Co-O Heterostructures on Silicon via Template Growth"; <i>320 Applied Physics Letters</i> ; 63(1993); 27 December; No. 26; pp. 3592-3594		
Examiner		Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

NOV 07 2003
U.S. PATENT & TRADEMARK OFFICE

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	IIAA	K. Eisenbeiser; "Field Effect Transistors with SrTiO ₃ Gate Dielectric on Si"; Applied Physics Letters; Vol. 76, No. 10; March 6, 2000; pp. 1324-1326					
	IIBB	Stephen A. Mass; "Microwave Mixers"; Second Edition; 2pp.					
	IICB	Douglas J. Hamilton et al.; "Basic Integrated Circuit Engineering"; pp.2; 1975					
	IIDB	Takeshi Obata; "Tunneling Magnetoresistance at Up to 270 K in La _{0.8} Sr _{0.2} MnO ₃ /SrTiO ₃ /La _{0.8} Sr _{0.2} MnO ₃ Junctions with 1.6-nm-Thick Barriers"; Applied Physics Letters; Vol. 74, No. 2; 11 January 1999; pp. 290-292					
	IIAE	Wei Zhang et al.; "Enhanced Magnetoresistance in La-Ca-Mn-O Films on Si Substrates Using YBaCuO/CeO ₂ Heterostructures"; Physica C; Vol. 282-287, No. 2003; 1 August 1997; pp. 1231-1232					
	IIAF	Shogo Imada et al.; "Epitaxial Growth of Ferroelectric YmnO ₃ Thin Films on Si (111) Substrates by Molecular Beam Epitaxy"; Jpn. J. Appl. Phys. Vol. 37 (1998); pp. 6497-6501; Part 1, No. 12A, December 1998					
	IIBG	Ladislav Pust et al.; "Temperature Dependence of the Magnetization Reversal in Co(fcc)-BN-Co(poly hcp) Structures"; Journal of Applied Physics; Vol. 85, No. 8; 15 April 1999; pp. 5765-5767					
	IIAH	C. Martinez; "Epitaxial Metallic Nanostructures on GaAs"; Surface Science; Vol. 482-485; pp. 910-915; 2001					
	IIAI	Wen-Ching Shih et al.; "Theoretical Investigation of the SAW Properties of Ferroelectric Film Composite Structures"; IEEE Transactions of Ultrasonics, Ferroelectrics, and Frequency Control; Vol. 45, No. 2; March 1998; pp. 305-316					
	IIAJ	Zhu Dazhong et al.; "Design of ZnO/SiO ₂ /Si Monolithic Integrated Programmable SAW Filter"; Proceedings of Fifth International Conference on Solid-State and Integrated Circuit Technology; 21-23; October 1998; pp. 826-829					
	IIAK	Kirk-Othmer Encyclopedia of Chemical Technology; Fourth Edition, Vol. 12; Fuel Resources to Heat Stabilizers; A Wiley-Interscience Publication; John Wiley & Sons					
	IIAL	Joseph W. Goodman et al; "Optical Interconnections For VLSI Systems"; Proceedings of the IEEE, Vol. 72, No. 7 July 1984					
	IIAM	Fathimulla et al.; "MONOLITHIC INTEGRATION OF InGaAs/InAlAs MODFETs and RTDs on InP-bonded-to Si SUBSTRATE"; Fourth International Conference on Indium Phosphide and Related Materials, Newport, RI, USA; April 21-24, 1992; pp. 167-170; XP000341253; IEEE, New York, NY, USA; ISBN: 0-7803-0522-1					
	IIAN	H. Takahashi et al.; "Arrayed-Waveguide Grating For Wavelength Division Multi/Demultiplexer With Nanometre Resolution"; Electronics Letters; Vol. 26., No. 2, 18th January 1990					
	IIAO	Pierret, R.F.; "1/J-FET and MESFET"; Field Effect Devices; MA, Addison-Wesley; 1990; pp. 9-22					
	IIAP	M. Schreiter, et al.; "Sputtering of Self-Polarized PZT Films for IR-Detector Arrays"; 1998 IEEE; pp. 181-185					
	IIAQ	Hideaki Adachi et al.; "Sputtering Preparation of Ferroelectric PLZT Thin Films and Their Optical Applications"; IEEE Transactions of Ultrasonics, Ferroelectrics and Frequency Control, Vol. 38, No. 6, November 1991					
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	JJAA	A.J. Moulson et al.; "Electroceramics Materials Properties Applications"; Chapman & Hall; pp. 366-369					
	JJAB	P.A. Langjahr et al.; "Epitaxial Growth and Structure of Cubic and Pseudocubic Perovskite Films on Perovskite Substrates"; Mat. Res. Soc. Symp. Proc., Vol. 401; 1995 Materials Research Society; pp. 109-114					
	JJAC	Wang et al.; "Depletion-Mode GaAs MOSFETs with Negligible Drain Current Drift and Hysteresis"; Electron Devices Meeting, 1998, IEDM '98 Technical Digest; pp. 67-70					
	JJAD	Ben G. Streetman; "Solid State Electronic Devices"; 1990, Prentice Hall; Third Edition; pp. 320-322					
	JJAE	A.Y. Wu et al.; "Highly Oriented (Pb,Lu)(Zr,Ti)O ₃ Thin Films on Amorphous Substrates"; IEEE, 1992; pp. 301-304					
	JJAF	Timothy E. Glassman et al.; "Evidence for Cooperative Oxidation of MoCVD Precursors Used in Ba _x Sr _{1-x} TiO ₃ Film Growth"; Mat. Res. Soc. Symp. Proc. Vol. 446, 1997 Materials Research Society; pp. 321-326					
	JJAG	S.N. Subbarao et al.; "Monolithic PIN Photodetector and FET Amplifier on GaAs-os-Si"; IEEE; GaAs IC Symposium-163-166; 1989					
	JJAH	T.A. Langdo et al.; "High Quality Ge on Si by Epitaxial Necking"; Applied Physics Letters; Vol. 76, No. 25; pp. 3700-3702; June 19, 2000					
	JJAI	Chenning Hu et al.; Solar Cells From Basics to Advanced Systems; McGraw-Hill Book Company; 1983					
	JJAJ	O.J. Painter et al.; "Room Temperature Photonic Crystal Defect Lasers at Near-Infrared Wavelengths in InGaAsP"; Journal of Lightwave Technology, Vol. 17, No. 11; November 1999					
	JJAK	C. Donn et al.; "A 16-Element, K-Band Monolithic Active Receive Phased Array Antenna"; Antennas and Propagation Society International Symposium, 1988; pp.188-191, Vol. 1; 6-10 June 1988					
	JJAL	Don W. Shaw; "Epitaxial GaAs on Si: Progress and Potential Applications"; Mat. Res. Soc. Symp. Proc.; pp.15-30; 1987					
	JJAM	G.J.M. Dormans, et al.; "PbTiO ₃ /Thin Films Grown by Organometallic Chemical Vapour Deposition"; Third International Symposium on Integrated Ferroelectrics; April 3-5, 1991 (Abstract)					
	JJAN	P.J. Borrelli et al.; "Compositional and Structural Properties of Sputtered PLZT Thin Films"; Ferroelectric Thin Films II Symposium; Dec. 2-4, 1991 (Abstract)					
	JJAO	Ranu Nayak et al.; "Enhanced acousto-optic diffraction efficiency in a symmetric SrTiO ₃ /BaTiO ₃ /SrTiO ₃ thin-film heterostructure"; 1 November 2000; Vol. 39, No. 31; Applied Optics; pp. 5847-5853					
	JJAP	Ranu Nayak et al.; "Studies on acousto-optical interaction in SrTiO ₃ /BaTiO ₃ /SrTiO ₃ epitaxial thin film heterostructures"; J. Phys. D: Appl. Phys. 32 (1999) 380-387					
	JJAQ	S.K. Tewksbury et al.; "Cointegration of Optoelectronics and Submicron CMOS"; Wafer Scale Integration; 1993; Proceedings, Fifth Annual IEEE; 20 January 1993; pp. 358-367					
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	KKAA	V. Kaushik et al.; "Device Characteristics of Crystalline Epitaxial Oxides on Silicon"; Device Research Conference, 2000; Conference Digest 58th DRC; pp. 17-20; June 19-21, 2000					
	KKAB	Katherine Derbyshire; "Prospects Bright for Optoelectronics Volume, Cost Drive Manufacturing for Optical Applications"; Semiconductor Magazine; Vol. 3, No. 3; March 2002					
	KKAC	Alex Chediak et al; "Integration of GaAs/Si with Buffer Layers and Its Impact on Device Integration"; TICS 4, Prof. Sands. MSE 225, April 12, 2002; pp. 1-5					
	KKAD	S.A. Chambers et al; "Band Discontinuities at Epitaxial SrTiO ₃ /Si(001) Heterojunctions"; Applied Physics Letters; Vol. 77, No. 11; September 11, 2000; pp. 1662-1664					
	KKAE	H. Wang et al.; "GaAs/GaAlAs Power HBTs for Mobile Communications"; Microwave Symposium Digest; 1993 IEEE; Vol. 2.; pp. 549-552					
	KKAF	Y. Ota et al.; "Application of Heterojunction FET to Power Amplifier for Cellular Telephone"; Electronics Letters; 26th May 1994; Vol. 30, No. 11; pp. 906-907					
	KKAG	Keiichi Sakuno et al; "A 3.5W HBT MMIC Power Amplifier Module for Mobile Communications"; IEEE 1994; Microwave and Millimeter-Wave Monolithic Circuits Symposium; pp. 63-66					
	KKAH	Mitsubishi Semiconductors Press Release (GaAs FET's) November 8, 1999 pp.1-2					
	KKAI	R.J. Matyi et al; "Selected Area Heteroepitaxial Growth of GaAs on Silicon for Advanced Device Structures"; 2194 Thin Solid Films; 181 (1989) December 10; No. 1; pp. 213-225					
	KKAJ	K. Nashimoto et al; "Patterning of Nb, LaOnZr, TiO ₃ Waveguides for Fabricating Micro-Optics Using Wet Etching and Solid-Phase Epitaxy"; Applied Physics Letters; Vol. 75, No. 8; 23 August 1999; pp. 1054-1056					
	KKAK	Bang-Hung Tsao et al; "Sputtered Barium Titanate and Barium Strontium Titanate Films for Capacitor Applications"; Applications of Ferroelectrics, 2000; Proceedings of the 2000 12th International Symposium on Vol. 2; pp. 837-840					
	KKAL	Man Fai Ng et al; "Heteroepitaxial growth of lanthanum aluminate films derived from mixed metal nitrates"; Journal of Materials Research; Vol. 12, No. 5; pp. 1306					
	KKAM	Yuji Matsumoto et al.; "Room-Temperature Ferromagnetism in Transparent Transition Metal-Doped Titanium Dioxide"; Science; 2 February 2001; Vol. 291; pp. 854-856					
	KKAN	S.A. Chambers et al.; "Epitaxial Growth and Properties of Ferromagnetic Co-Doped TiO ₂ Anatase"; Applied Physics Letters; Vol. 79, No. 21; November 19, 2001; pp. 3467-3469					
	KKAO						
	KKAP						
	KKAQ						
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

NOV 07 2003
U.S. PATENT & TRADEMARK OFFICE

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

November 6, 2001

GROUP

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	UT	5,528,209	06/18/96	Macdonald et al.			
	UV	5,998,781	12/07/99	Vawter et al.			
	UW	6,110,813	08/29/00	Ota et al.			
	UX	6,452,232 B1	09/17/02	Adan			
	UY	6,049,110	04/11/00	Koh			
	UZ	5,559,368	09/24/96	Hu et al.			
	VA	6,392,253 B1	05/21/02	Saxena			
	VB	5,585,288	12/17/96	Davis et al.			
	VC	5,268,327	12/07/93	Vernon			
	VD	6,198,119 B1	03/06/01	Nabatame et al.			
	VE	6,113,225	09/05/00	Miyata et al.			
	VF	5,262,659	11/16/93	Grudkowski et al.			
	VG	6,239,012 B1	05/29/01	Kinsman			
	VH	6,297,598	10/02/01	Wang et al.			
	VI	2002/140012	10/03/02	Droopad			
	VJ	4,866,489	09/12/89	Yokogawa et al.			
	VK	6,080,378	06/27/00	Yokota et al.			
	VL	5,508,554	04/16/96	Takatani et al.			
	VM	6,477,285 B1	11/05/02	Shanley			
	VN	4,695,120	09/22/87	Holder			
	VO	5,882,948	03/16/99	Jewell			
	VP	5,574,589	11/12/96	Feuer et al.			
	VQ	5,510,665	04/23/96	Conley			
	VR	4,804,866	02/14/89	Akiyama			
	VS	5,057,694	10/15/91	Idaka et al.			
	VT	5,635,453	06/03/97	Pique et al.			
	VU	5,719,417	02/17/98	Roeder et al.			
	VV	5,998,819	12/07/99	Yokoyama et al.			

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

NOV 07 2003
U.S. PATENT & TRADEMARK OFFICE

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
215686US99CIPSERIAL NO.
09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Fred RICHARD, et al.FILING DATE
November 6, 2001GROUP
2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	VW	2002/0079576	06/27/02	Seshan			
	VX	5,148,504	09/15/92	Levi et al.			
	VY	2002/0195610 A1	12/26/02	Klosowiak			
	VZ	5,477,363	12/19/95	Matsuda			
	WA	5,905,571	05/18/99	Butler et al.			
	WB	5,570,226	10/29/96	Ota			
	WC	5,087,829	02/11/92	Ishibashi et al.			
	WD	2001/0020278 A1	09/06/01	Saito			
	WE	6,496,469 B1	12/17/02	Uchizaki			
	WF	5,679,947	10/21/97	Doi et al.			
	WG	2001/0036142 A1	11/01/01	Kadowaki et al.			
	WH	5,446,719	08/29/95	Yoshida et al.			
	WI	5,831,960	11/03/98	Jiang et al.			
	WJ	5,693,140	12/02/97	McKee et al.			
	WK	6,376,337 B1	04/23/02	Wang et al.			
	WL	4,177,094	12/04/79	Kroon			
	WM	5,216,359	06/01/93	Makki et al.			
	WN	6,307,996 B1	10/23/01	Nashimoto et al.			
	WO	5,371,621	12/06/94	Stevens			
	WP	2002/0145168 A1	10/10/02	Bojarczuk, Jr et al.			
	WQ	3,617,951	11/02/71	Anderson			
	WR	5,838,053	11/17/98	Bevan et al.			
	WS	5,684,302	11/04/97	Wersing et al.			
	WT	5,959,308	09/28/99	Shichijo et al.			
	WU	5,362,972	11/08/94	Yazawa et al.			
	WV	5,864,171	01/26/99	Yamamoto et al.			
	WW	5,028,563	07/02/91	Feit et al.			
	WX	5,937,115	08/10/99	Domash			

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

215686US99CIP

SERIAL NO.

09/985,757

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Fred RICHARD, et al.

FILING DATE

November 6, 2001

GROUP

2811

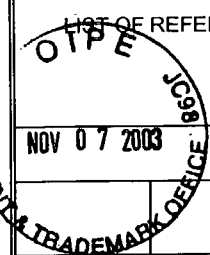
U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	WY	5,878,175	03/02/99	Sonoda et al.			
	WZ	4,801,184	01/31/89	Revelli			
	XA	5,140,387	08/18/92	Okazaki et al.			
	XB	5,410,622	04/25/95	Okada et al.			
	XC	6,064,783	05/16/00	Congdon et al.			
	XD	5,772,758	06/30/98	Collins et al.			
	XE	5,666,376	09/09/97	Cheng			
	XF	5,976,953	11/02/99	Zavracky et al.			
	XG	5,578,162	11/26/96	D'Asaro et al.			
	XH	5,585,167	12/17/96	Satoh et al.			
	XI	5,674,813	10/07/97	Nakamura et al.			
	XJ	5,574,296	11/12/96	Park et al.			
	XK	6,504,189	01/07/03	Matsuda et al.			
	XL	5,987,196	11/16/99	Noble			
	XM						
	XN						
	XO						
	XP						
	XQ						
	XR						
	XS						
	XT						
	XU						
	XV						
	XW						
	XX						
	XY						
	XZ						

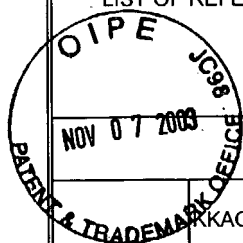
Examiner

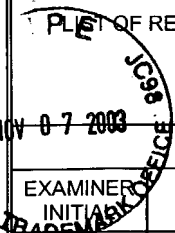
Date Considered

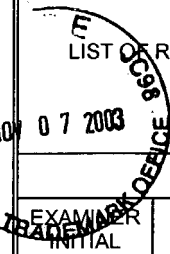
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
				FOREIGN PATENT DOCUMENTS			
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
	CBC EP 1 035 759	09/13/00	Europe				
	CBD EP 0 860 913	08/26/95	EUROPE				
	CBE 5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT				
	CBF 5-243525	09/31/93	JAPAN W/ENGLISH ABSTRACT				
	CBG 3-171617	07/25/91	JAPAN W/ENGLISH ABSTRACT				
	CBH EP 1 089 338	04/04/01	EUROPE				
	CBI 01 294594	11/28/99	JAPAN (ABSTRACT)				
	CBJ 05 221800	08/31/93	JAPAN (ABSTRACT)				
	CBK 03-149882	11/07/89	JAPAN				
	CBL 0 614 256	09/07/94	EUROPE				
	CBM 1 054 442	11/22/00	EUROPE				
	CBN 0 852 416	07/08/98	EUROPE				
	CBO WO 02/08806	01/31/02	WIPO				
	CBP WO 01/59837	08/16/01	WIPO				
	CBQ 62-245205	10/26/87	JAPAN W/ENGLISH ABSTRACT				
	CBR 0 600 658	06/08/94	EUROPE				
	CBS 0 412 002	02/06/91	EUROPE				
	CBT 2000-349278	12/15/00	JAPAN (ENGLISH ABSTRACT)				
	CBU 01-196809	08/08/89	JAPAN (ENGLISH ABSTRACT)				
	CBV 0 619 283	10/12/94	EUROPE				
	CBW 0 661 561	07/05/95	EUROPE				
	CBX 0 331 338	09/06/89	EUROPE				
	CBY						
	CBZ						
	CCA						
	CCB						
	CCC						
	CCD						
	CCE						
	CCF						
	CCG						
	CCH						
	CCI						
	CCJ						
	CCK						
	CCL						
	CCM						
	CCN						
	CCO						

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
				OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
	KKAO	Charles Kittel; "Introduction to Solid State Physics"; John Wiley & Sons, Inc. Fifth Edition; pp. 415					
	KKAP	Chyuan-Wei Chen et al; "Liquid-phase epitaxial growth and characterization of InGaAsP layers grown on GaAsP substrates for application to orange light-emitting diodes"; 931 Journal of Applied Physics; 77 (1995) 15 January, No. 2; Woodbury, NY, US; pp. 905-909					
	KKAQ	W. Zhu et al.; "Oriented diamond films grown on nickel substrates"; 320 Applied Physics Letters; 63(1993) September, No. 12, Woodbury, NY, US; pp. 1640-1642					
	KKAR	M. Schreck et al.; "Diamond/Ir/SrTiO ₃ : A material combination for improved heteroepitaxial diamond films"; Applied Physics Letters; Vol. 74, No. 5; February 1, 1999; pp. 650-652					
	KKAS	Yoshihiro Yokota et al.; "Cathodoluminescence of boron-doped heteroepitaxial diamond films on platinum"; Diamond and Related Materials 8(1999); pp. 1587-1591					
	KKAT	J.R. Busch et al.; "LINEAR ELECTRO-OPTIC RESPONSE IN SOL-GEL PZT PLANAR WAVEGUIDE"; Electronics Letters; 13th August 1992; Vol. 28, No. 17; pp. 1591-1592					
	KKAU	R. Droopad et al; "Epitaxial Oxide Films on Silicon: Growth, Modeling and Device Properties"; Mat. Res. Soc. Symp. Proc. Vol. 619; 2000 Materials Research Society; pp. 155-165					
	KKAV	H. Ohkubo et al.; "Fabrication of High Quality Perovskite Oxide Films by Lateral Epitaxy Verified with RHEED Oscillation"; 2419A Int. Conf. on Solid State Devices & Materials, Tsukuba, August 26-28 (1992); pp. 457-459					
	KKAW	Lin Li; "Ferroelectric/Superconductor Heterostructures"; Materials Science and Engineering; 29 (2000) pp. 153-181					
	KKAX	L. Fan et al.; "Dynaamic Beam Switching of Vertical-Cavity Surface-Emitting Lasers with Integrated Optical Beam Routers"; IEEE Photonics Technology Letters; Vol. 9, No. 4; April 4, 1997; pp. 505-507					
	KKAY	Y. Q. Xu. et al.; "(Mn, Sb) dropped-Pb(Zr,Ti)O ₃ infrared detector arrays"; Journal of Applied Physics; Vol. 88, No. 2; 15 July 2000; pp. 1004-1007					
	KKAZ	Kiyoko Kato et al.; "Reduction of dislocations in InGaAs layer on GaAs using epitaxial lateral overgrowth"; 2300 Journal of Crystal Growth 115 (1991) pp. 174-179; December 1991					
	LLAA						
	LLAB						
	LLAC						
	LLAD						
	LLAE						
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	XN	6,233,435 B1	05/15/01	WONG			
	XO	4,723,321	02/02/88	SALEH			
	XP	6,181,920 B1	01/30/01	DENT ET AL			
	XQ	6,415,140 B1	07/02/02	BENJAMIN ET AL			
	XR	5,760,740	06/02/98	BLODGETT			
	XS	5,238,877	08/24/93	RUSSELL			
	XT	4,876,218	10/24/89	PESSA ET AL			
	XU	6,232,242 B1	05/15/01	HATA ET AL			
	XV	4,378,259	03/29/83	HASEGAWA ET AL			
	XW	6,278,541 B1	08/21/01	BAKER			
	XY	4,298,247	11/03/81	MICHELET ET AL			
	XZ	4,174,504	11/13/79	CHENAUSSKY ET AL			
	YA	3,758,199	09/11/73	THAXTER			
	YB	6,362,558 B1	03/26/02	FUKUI			
	YC	6,140,746	10/31/00	MIYASHITA ET AL			
	YD	2002/0076878 A1	06/20/02	WASA ET AL			
	YE	6,419,849 B1	07/16/02	QIU ET AL			
	YF	2002/0179000 A1	12/05/02	LEE ET AL			
	YG	6,341,851	01/29/02	TAKAYAMA ET AL			
	YH	2001/0055820 A1	12/27/01	SAKURAI ET AL			
	YI	6,204,525 B1	03/20/01	SAKURAI ET AL			
	YJ	5,985,404	11/16/99	YANO ET AL			
	YK	6,538,359 B1	03/25/03	HIRAKU ET AL			
	YL	6,498,358 B1	12/24/02	LACH ET AL			
	YM	5,387,811	02/07/95	SAIGO			
	YN	5,523,602	06/04/96	HORIUCHI ET AL			
	YO	5,362,998	11/08/94	IWAMURA ET AL			
	YP	5,188,976	02/23/93	KUME ET AL			
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
<div style="text-align: center;">  <p>LIST OF REFERENCES CITED BY APPLICANT</p> </div>				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	YQ	6,501,121 B1	12/31/02	YU ET AL			
	YR	5,919,515	07/06/99	YANO ET AL			
	YS	5,238,877	08/24/93	RUSSELL			
	YT	5,540,785	07/30/96	DENNARD ET AL			
	YU	5,997,638	12/07/99	COPEL ET AL			
	YV	6,291,866	09/18/01	WALLACE			
	YW	5,365,477	11/15/94	COOPER, JR ET AL			
	YX	5,548,141	08/20/96	MORRIS ET AL			
	YY	2002/0021855	02/21/02	KIM			
	YZ	6,110,840	08/29/00	YU			
	ZA	5,667,586	09/16/97	EK ET AL			
	ZB	5,313,058	05/17/94	FRIEDERICH ET AL			
	ZC	5,315,128	05/24/94	HUNT ET AL			
	ZD	5,919,522	07/06/99	BAUM ET AL			
	ZE	4,843,609	06/27/89	OHYA ET AL			
	ZF	4,626,878	12/02/86	KUWANO ET AL			
	ZG	4,525,871	06/25/85	FOYT ET AL			
	ZH	3,818,451	06/18/74	COLEMAN			
	ZI	6,059,895	05/09/00	CHU ET AL			
	ZJ	4,447,116	05/08/84	KING ET AL			
	ZK	6,022,671	02/08/00	BINKLEY ET AL			
	ZL	5,754,714	05/19/98	SUZUKI ET AL			
	ZM	6,524,651 B2	02/25/03	GAN ET AL			
	ZN	6,355,945 B1	03/12/03	KADOTA ET AL			
	ZO	5,642,371	06/24/97	TOHYAMA ET AL			
	ZP	6,445,724 B2	09/03/02	ABELES			
	ZQ	5,753,934	05/19/98	YANO ET AL			
	ZR	6,326,667 B1	12/04/01	SUGIYAMA ET AL			
	ZS	6,051,874	04/18/00	MASUDA			
	ZT	5,166,761	11/24/92	OLSON ET AL			
	ZU	5,574,744	11/12/96	GAW ET AL			
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

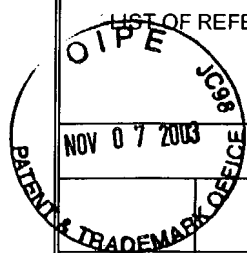
Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
215686US99CIPSERIAL NO.
09/985,757

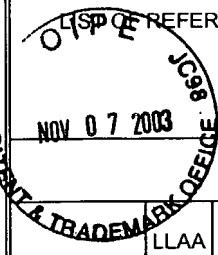
LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Fred RICHARD, et al.FILING DATE
November 6, 2001GROUP
2811

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	CCA	5-238894	09/17/93	JAPAN W/ENGLISH ABSTRACT		
	CCB	2 152 315	07/31/85	GREAT BRITAIN		
	CCC	2001-196892	07/19/01	JAPAN W/ENGLISH ABSTRACT		
	CCD	2000-278085	10/06/00	JAPAN (ENGLISH ABSTRACT)		
	CCE	WO 03/012874	02/13/03	WIPO		
	CCF	1 043 427	10/11/00	EUROPE		
	CCG	1 069 605	01/17/01	EUROPE		
	CCH	WO 02/099885	12/12/02	WIPO		
	CCI	10-269842	10/09/98	JAPAN W/ENGLISH ABSTRACT		
	CCJ	59066183	04/14/84	JAPAN (ENGLISH ABSTRACT)		
	CCK	03046384	02/27/91	JAPAN (ENGLISH ABSTRACT)		
	CCL	WO 02/11254	02/07/02	WIPO		
	CCM	0 494 514	07/15/92	EUROPE		
	CCN	0 247 722	12/02/87	EUROPE		
	CCO	1 037 272	09/20/00	EUROPE		
	CCP	59-073498	04/25/84	JAPAN (ENGLISH ABSTRACT)		
	CCQ	60-161635	08/23/85	JAPAN W/ENGLISH ABSTRACT		
	CCR	59-044004	03/12/84	JAPAN W/ENGLISH ABSTRACT		
	CCS	0 392 714	10/17/90	EUROPE		
	CCT					
	CCU					
	CCV					
	CCW					
	CCX					
	CCY					
	CCZ					
	CDA					
	CDB					
	CDC					
	CDD					
	CDE					
	CDF					
	CDG					
	CDH					
	CDI					
	CDJ					
	CDK					
	CDL					
	CDM					
	CDN					



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 215686US99CIP		SERIAL NO. 09/985,757	
LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Fred RICHARD, et al.			
				FILING DATE November 6, 2001		GROUP 2811	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	LLAA	Peter Weiss; "Speed demon gets hooked on silicon"; Science News Online; Sept. 15, 2001; pp. 1-3					
	LLAB	"Motorola Develops New Super-Fast Chip"; USA Today; Sept. 4, 2001					
	LLAC	Lori Valigra; "Motorola Lays GaAs on Si Wafer"; AsiaBizTech; Nov. 2001pp. 1-3					
	LLAD	"Holy Grail! Motorola Claims High-Yield GaAs Breakthrough"; Micromagazine.com (no date available); pp. 1-3					
	LLAE	Jong-Gul YOON; "Growth of Ferroelectric LiNbO ₃ Thin Film on MgO-Buffered Si by the Sol-Gel Method"; Journal of the Korean Physical Society (Proc. Suppl.); Vol. 29, Nov. 1996; pp. S648-S651					
	LLAF	V. Bormand et al.; "Deposition of LiTaO ₃ thin films by pyrosol process"; Thin Solid Films 304 (1997); pp.239-244					
	LLAG	R. Droopad et al.; "Development of high dielectric constant epitaxial oxides on silicon by molecular beam epitaxy"; Materials Science and Engineering B87 (2001); pp.292-296					
	LLAH	A.K. Sharma et al.; "Integration of Pb(Zr _{0.52} Ti _{0.48})O ₃ epilayers with Si by domain epitaxy"; Applied Physics Letters, Vol. 76, No. 11; March 13, 2000; pp. 1458-1460					
	LLAI	Dwight C. Streit et al; "High Reliability GaAs-AlGaAs HBT's by MBE with Be Base Doping and InGaAs Emitter Contacts"; 8179 IEEE Electron Device Letters; 12(1991) September, No. 9, New York, US					
	LLAJ	C. Y. Hung et al; "Piezoelectrically induced stress tuning of electro-optic devices"; 320 Applied Physics Letters; 59(1991) 30 December, No. 27, New York, US					
	LLAK	J. Piprek; "Heat Flow Analysis of Long-Wavelength VCSELs with Various DBR Materials"; University of Delaware, Materials Science, Newark, DE, 19716-3106; Oct. 31, 1994; pp. 286-287					
	LLAL	P. Mackowiak et al.; "Some aspects of designing an efficient nitride VCSEL resonator"; J. Phys. D: Appl. Phys. 34(2001); pp. 954-958					
	LLAM	M.R. Wilson et al.; GaAs-On-Si: A GaAs IC Manufacturer's Perspective"; GaAs IC Symposium, IEEE, 1988; pp. 243-246					
	LLAN	Y. Kitano et al.; "Thin film crystal growth of BaZrO ₃ at low oxygen partial pressure"; Journal of Crystal Growth 243 (2002); pp. 164-169					
	LLAO	M.E. Hawley; et al; "Microstructural Study of Colossal Magneto-Resistive Films As a Function of Growth Temperature, As Deposited and Annealed"; 401, 1996; pp. 531-536					
	LLAP						
	LLAQ						
Examiner						Date Considered	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							